## High current coated conductors based on IBAD MgO and PLD YBCO

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# One of our plans for this year was to identify and attempt to overcome limitations to thick film $J_c$

- Approach the drop in  $J_c$  with thickness as though it is a materials-processing issue, and not intrinsic. At a particular thickness, maximize  $J_c$  through a comprehensive process optimization. *Goal: Reproducible achievement of I\_cs over 400 A/cm-width at a film thickness of*  $\leq 1.5 \ \mu m$ .
  - Goal was met by optimizing the buffer layer deposition process.
  - ► Also developed a simple model for J<sub>c</sub> dependence on thickness.
  - ► Tested one prediction of model, significantly increasing I<sub>c</sub> beyond stated goal.

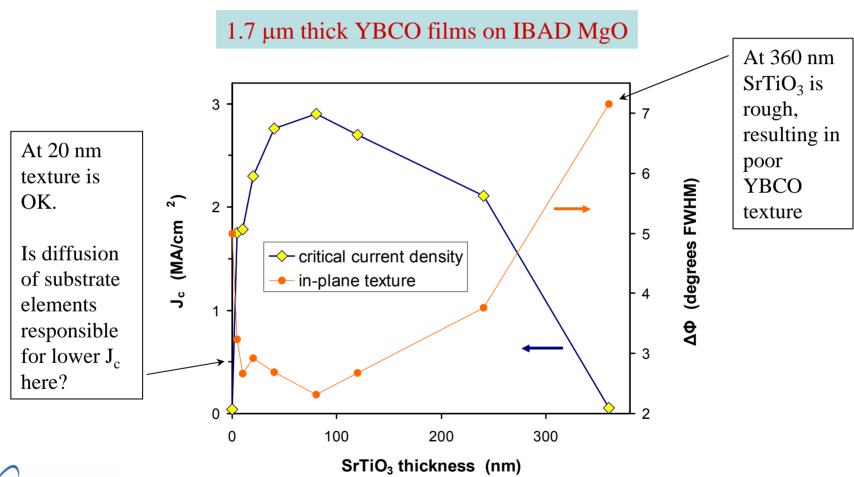


#### Process optimization focused on the laserdeposited SrTiO<sub>3</sub> buffer layer we use for IBAD MgO

- ► Changed to SrTiO<sub>3</sub> from SrRuO<sub>3</sub> last year.
- ► Initially used "standard" deposition conditions.
- ▶ Determined effect of buffer thickness on J<sub>c</sub> (similar to CeO<sub>2</sub> on IBAD YSZ).
- Discovered an unexpected dependence on deposition temperature.

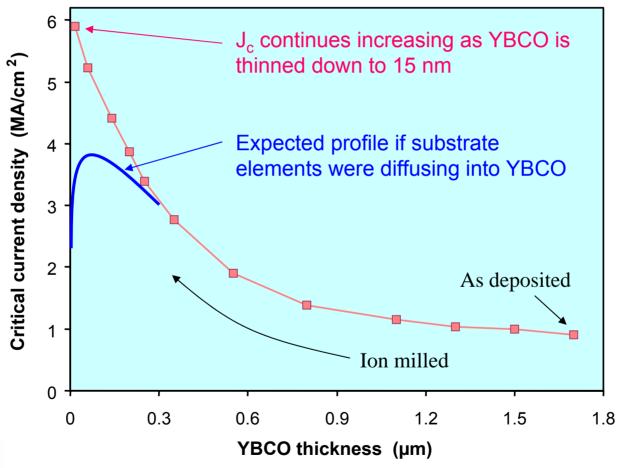


#### Optimum SrTiO<sub>3</sub> thickness is 40-120 nm





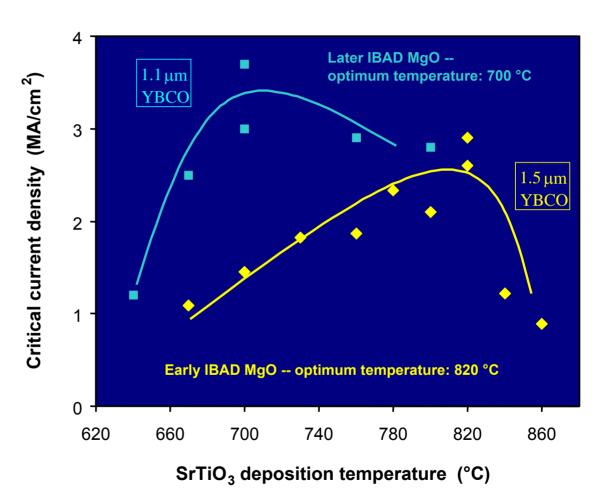
# lon milling reveals no diffusion problem, even for very thin SrTiO<sub>3</sub> (20 nm in this case).





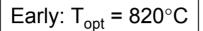
# Optimum SrTiO<sub>3</sub> deposition temperature can vary for different IBAD MgO runs, but peak J<sub>c</sub> values are similar

- ► YBCO texture
  is 2.4 3.6°
  FWHM inplane, and is
  unaffected by
  SrTiO<sub>3</sub>
  deposition
  temperature
- ▶ YBCO deposition temperature is 760°C for all samples.

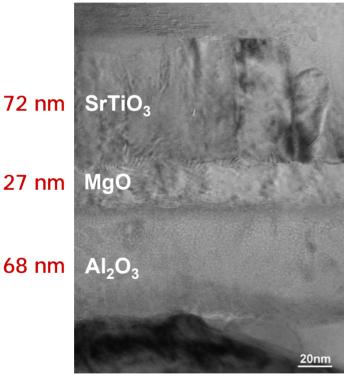


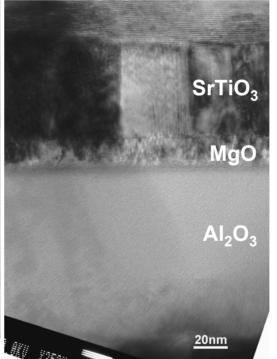


# TEM analysis revealed thickness differences in the oxide layer stack but not why the optimum SrTiO<sub>3</sub> temperature is different



Later:  $T_{opt} = 700^{\circ}C$ 





55 nm

19 nm

100 nm

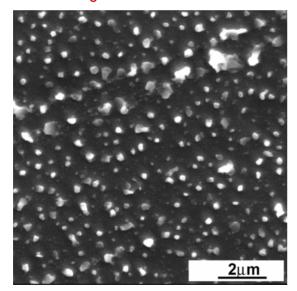


## In all cases, however, the highest J<sub>c</sub> results from the SrTiO<sub>3</sub> deposition temperature that yields the smoothest surface

SEMs show fewer SrTiO<sub>3</sub> outgrowths on the buffer layer surface at the optimum deposition temperature

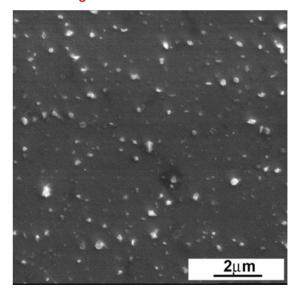
T<sub>dep</sub>: 670°C

J<sub>c</sub>: 1.1 MA/cm<sup>2</sup>



T<sub>dep</sub>: 820°C

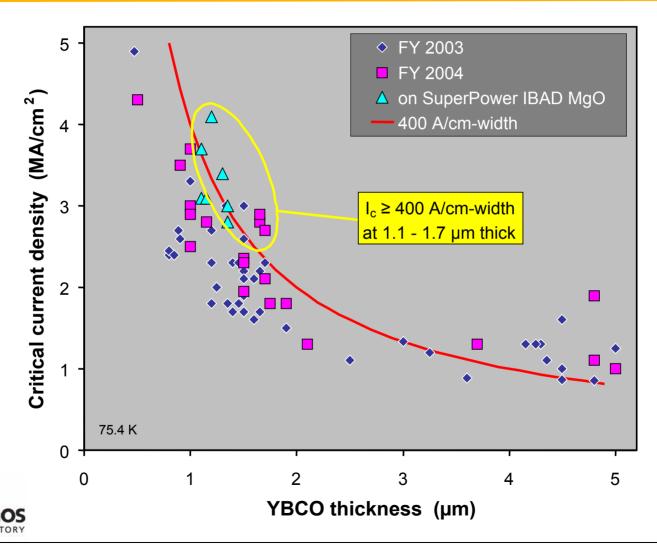
 $J_c$ : 3.0 MA/cm<sup>2</sup>



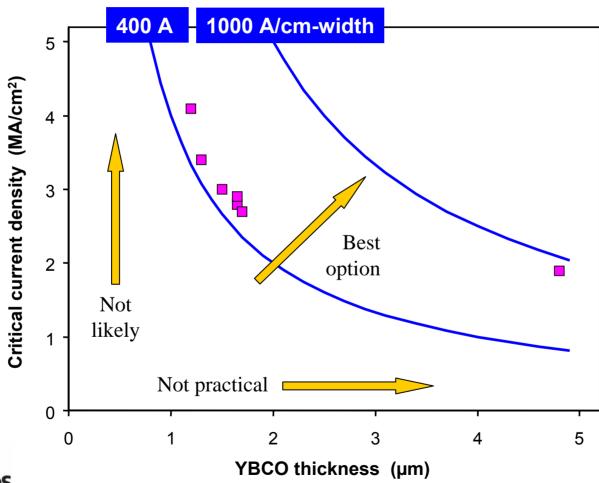


H. Wang, et al., J. Mater. Res. 19, 1869 (2004).

## Optimization of the SrTiO<sub>3</sub> buffer layer has allowed us to reach our goal of 400 A/cm-width @ 1.5 µm on IBAD MgO

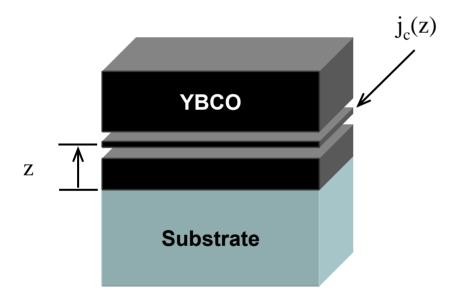


# Although optimization delivered incremental improvement a different approach is needed to reach higher current levels.





# Our effort to reach higher currents started with consideration of the *incremental* critical current density



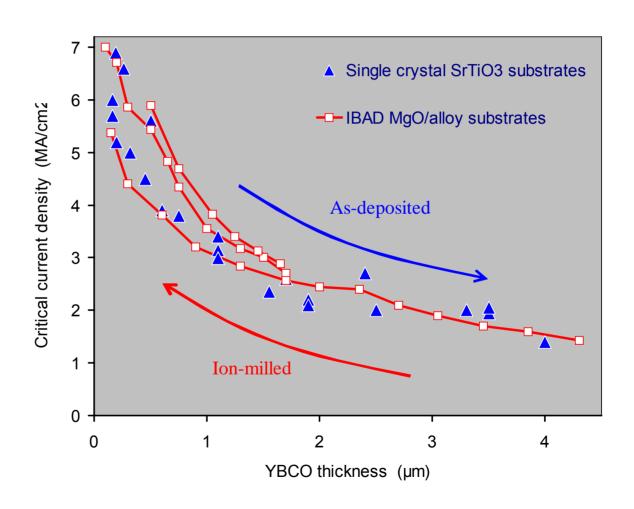
The incremental j<sub>c</sub> is the critical current density for a slice of YBCO that has been hypothetically isolated from the rest of the coating and measured.



# For PLD YBCO the incremental $j_c$ is established during film growth and is independent of total thickness

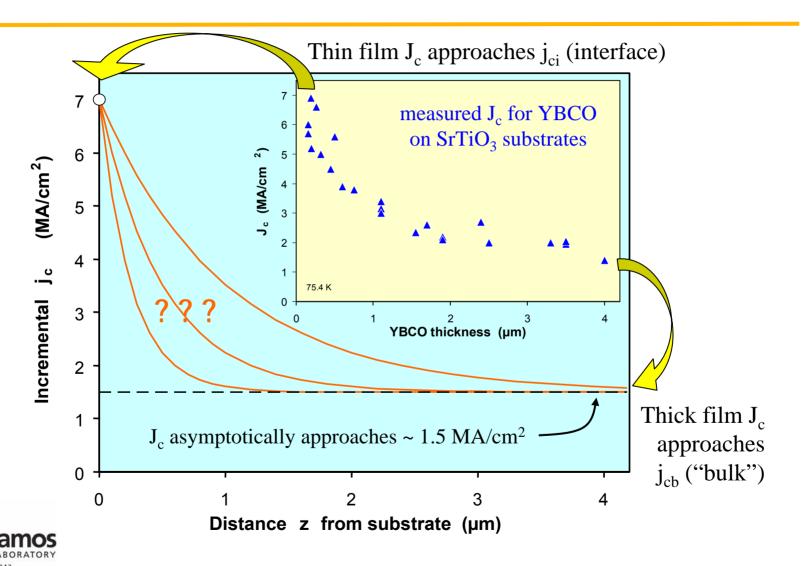
Trend is the same whether YBCO is being added or removed.

(These results also demonstrate the equivalence of J<sub>c</sub> for IBAD MgO and single-crystal substrates.)

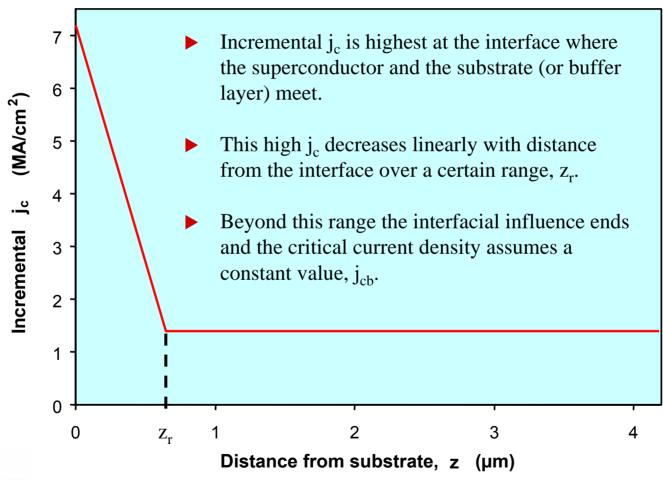




# There are two characteristic $j_c$ values for YBCO films that can be estimated from $J_c(t)$ plots

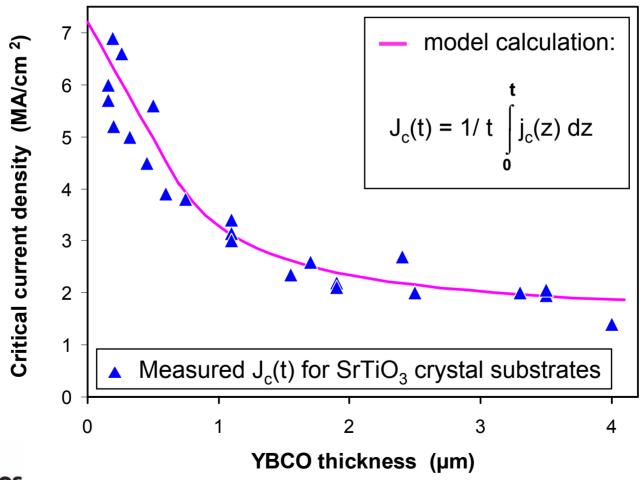


#### We began with the simplest possible $j_c(z)$ dependence ...





## ... and found that this dependence gives excellent agreement with measured J<sub>c</sub> values





## A possible explanation for the inherent or "bulk" $j_c$ for YBCO comes from recent work by B. Dam *et al.*

- ▶ Observed a high density of dislocations between 2D growth islands in PLD films.
- ▶ Dislocations are parallel to the c-axis and extend from near the substrate to the film surface.
- Density of dislocations is independent of YBCO thickness.

B. Dam, et al., Phys. Rev. B 65, 064528 (2002).

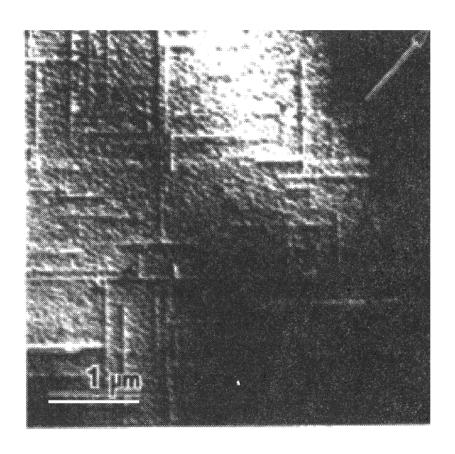


## The same work may provide a clue as to the source of high interfacial $j_c$

- ► The process that produces threading dislocations also produces misfit dislocations.
- ► These dislocations only populate the region near the interface.
- Although misfit dislocations lie mainly in the YBCO a-b plane, they create a cross-hatch pattern that may be effective at pinning flux perpendicular to the plane. (H. Safar, *et al.*, Appl. Phys. Lett. **68**, 1853 (1996)).



# Misfit dislocations are a common feature in heteroepitaxial film growth



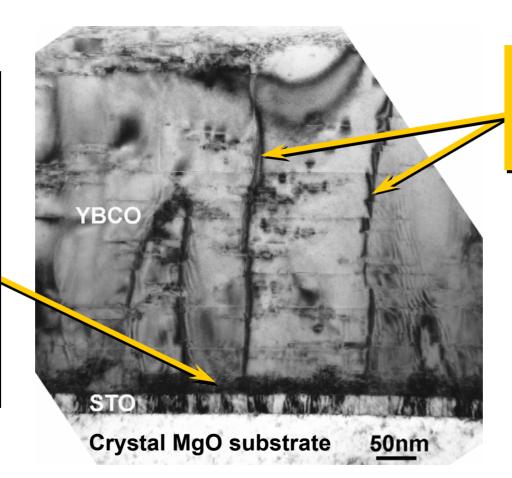
TEM plan view of misfit dislocations in a thin GeSi film on a (001) Si substrate.

J. Washburn, *et al.*, J. Electronic Mat. **20**, 155 (1991).



#### TEM cross section provides evidence for a high interfacial defect density

A 20 nmthick
region at
the
YBCOSrTiO<sub>3</sub>
interface
with a
high
density of
defects

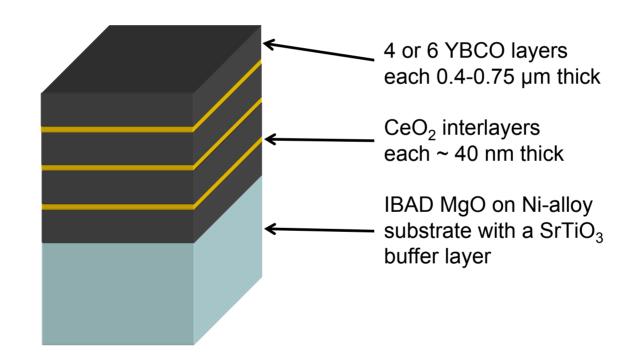


Threading dislocations between columns



# Regardless of the source of high interfacial $j_c$ the model predicts that extra interfaces will increase the average $J_c$ of YBCO

**To test:** Introduce extra heteroepitaxial interfaces using a YBCO (CeO<sub>2</sub>/YBCO)<sup>n</sup> multilayer design.





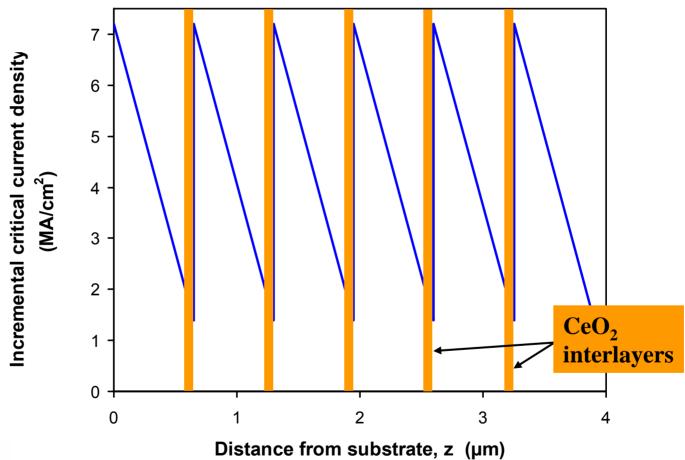
### The present work differs from our earlier multilayer work in both design and purpose

- Earlier work\* used multilayers to solve a porosity problem in films more than 1.5 μm thick. Initially CeO<sub>2</sub> interlayers were used, but we quickly switched to Sm 123.
- The porosity problem was ultimately solved by using smoother substrates (presented last year).
- ▶ In the present work the CeO<sub>2</sub> interlayers are thinner than before, allowing for electrical contact between YBCO layers.
- ► Each YBCO layer is thinner and therefore has higher J<sub>c</sub>.
- ► The purpose is to raise J<sub>c</sub> by imparting the high interfacial performance to a greater volume of the film.



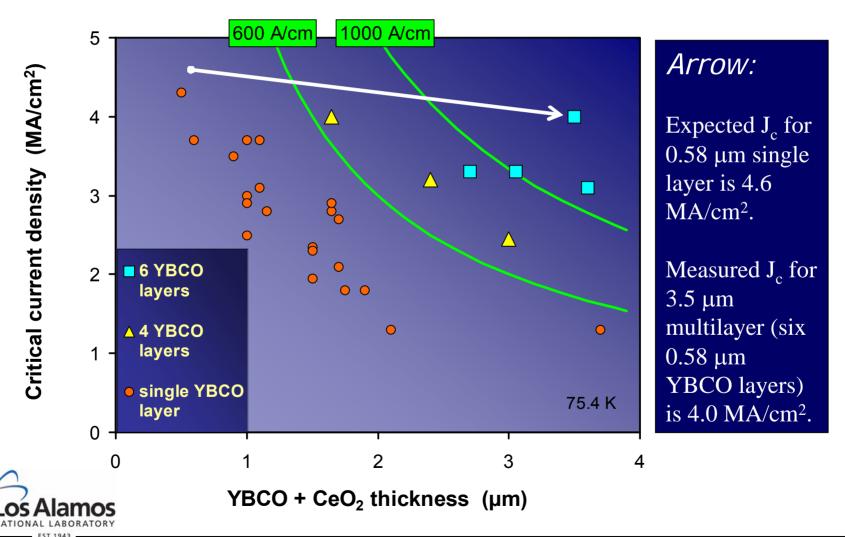
\* Q. X. Jia, et al., Appl. Phys. Lett. 80, 1601 (2002).

# The multilayer philosophy is to create multiple regions of high interfacial J<sub>c</sub> throughout the coating





#### The YBCO/CeO<sub>2</sub> multilayer approach significantly increases thickfilm J<sub>c</sub> and enables achievement of I<sub>c</sub> levels above 1000 A/cm-width



#### **Scoring criterion** – Results

- 1. Damage anisotropy experiments provided the first confirmation of IBAD MgO texturing mechanism.
- 2. Established a methodology to quantitatively determine impurity concentrations in YBCO films and measure the effect of substrate elements on superconducting properties.
- 3. For the first time measured diffusion coefficients of transition metal elements in alumina films, as used in our IBAD MgO architecture.



#### Scoring criterion – Results (continued)

- 4. Produced many films on IBAD MgO in the 1.1-1.7  $\mu$ m thickness range with  $I_c > 400$  A/cm-width.
- 5. Took a fresh look at the J<sub>c</sub> drop with YBCO thickness and significantly improved upon the situation by using YBCO-CeO<sub>2</sub> multilayers.
- 6. Highest current on IBAD MgO in 2003: 720 A/cm-width at 4.5 μm.

Highest multilayer currents on IBAD MgO in 2004:

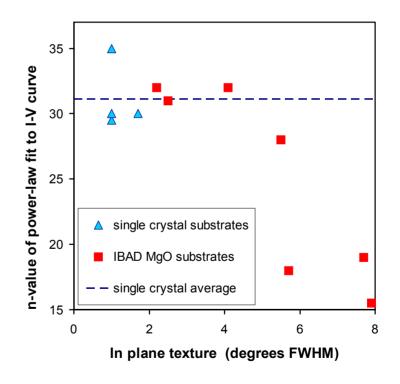
660 A/cm-width at 1.65 μm 1000-1400 A/cm-width at 3.1-3.6 μm.



- Experimentally investigate the fundamental texturing mechanisms of IBAD. Goal: Develop a model that will allow us to further refine IBAD deposition parameters and texture.
- Determined that damage induced by Ar ion irradiation of MgO exhibited an anisotropy that conformed to:  $\chi_{\text{max}}^{(110)} < \chi_{\text{max}}^{(100)} < \chi_{\text{max}}^{(111)}$ .
- ► Temperature dependent damage accumulation data implied that IBAD texturing would improve at low temperatures.
- ► Although optimum texturing was unchanged at low temperatures, the processing window was expanded.



- Use extended I-V curves for IBAD MgO to evaluate the validity of the bicrystal plateau analogy for coated conductors. *Goal: Determine whether improved texture will yield higher J\_cs*.
- Extended I-V curves proved to be less sensitive for IBAD than for bicrystals because of the large number of grain boundaries in the current path.
- ► However, the n-value (as in V = I<sup>n</sup>) is a good indicator of the transition to weak-link behavior at 4-5° FWHM.





- Approach the drop in  $J_c$  with thickness as though it is a materials-processing issue, and not intrinsic. At a particular thickness, maximize  $J_c$  through a comprehensive process optimization. *Goal: Reproducible achievement of I\_cs over 400 A/cm-width at a film thickness of*  $\leq$  1.5  $\mu$ m.
- Met this goal by optimizing the  $SrTiO_3$  buffer layer; however,  $J_c$  at 1.5 µm is still significantly less than that for very thin films.
- ► Took a fresh look at the thickness dependence of J<sub>c</sub> and concluded that extra interfaces inside the YBCO would be beneficial.
- ► Created extra interfaces using a multilayer design and reproducibly achieved the world's first I<sub>c</sub> levels greater than 1000 A/cm-width (75.5 K).



- Design and implement systematic experiments to determine if chemical modifications to REBCO offer enhanced performance, particularly in an external magnetic field. *Goal: Reproducibly double J\_c at 75 K in a magnetic field parallel to the c-axis*.
- ► This goal was met using two different approaches.
- ► One approach was the addition of BaZrO<sub>3</sub> to the PLD target, resulting in flux-pinning BZO nanoparticles in the films.
- A second approach resulted from a systematic study of mixed-rare-earth 123 compounds.
- ➤ See talk by Judith Driscoll and Leonardo Civale tomorrow in this session for details.



- Use ion-milling and SIMS to determine the quantitative tolerance of YBCO to diffusing substrate materials, and use this information to minimize the nonsuperconducting layer thickness. *Goal:* < 100 nm.
- Established a sound methodology, consisting of three parts to address this goal.
- 1. Developed a way to produce films with controllable impurity concentrations.
- 2. Selected Particle-Induced-X-ray-Emission (PIXE) to measure impurity concentrations. Measured concentrations of Ni in YBCO.
- 3. Used ion milling to test whether diffusion was a problem when very thin SrTiO<sub>3</sub> was used.



- Develop a single material that can serve as both a barrier and nucleation layer. Goal: Reduce the number of layers by one, and reduce the barrier/nucleation layer thickness by 20 nm, with no reduction in performance.
- Found a candidate that functions as both barrier and nucleation layer: Er<sub>2</sub>O<sub>3</sub>.
- ► However, we postponed this task while working to establish the means of quantitatively evaluating barrier properties of films (previous goal).
- ► We will consult with our industrial partners before continuing this task to determine their level of interest in a single barrier/nucleation layer.



- Continue using our 1 meter tape capability to supply IBAD MgO to industrial partners and other national laboratories, and work with them individually to achieve optimum YBCO performance. *Goal: Three organizations depositing YBCO with J<sub>c</sub>s equivalent to those on single-crystal substrates.*
- ▶ During the year SuperPower developed its own capability to continuously process high-quality IBAD MgO, and AMSC received lengths from the Research Park. These developments negated the need for the Core Program to supply lengths to partners.
- ► Single crystal equivalent  $J_c$ s were reached with our PLD YBCO on SuperPower's IBAD MgO  $\rightarrow$  300-400 A/cm-width @ 1.2-1.5 µm thick.



#### **Scoring criterion** – Research integration

- Our primary research integration activity this year was the transfer of IBAD MgO technology to SuperPower. This was accomplished by sample and information exchanges, equipment loans, and site visits.
- The result of this activity is that SuperPower (SP) has successfully implemented their own IBAD MgO capability in a very short time. Highlights:
- SP IBAD/LANL buffers & YBCO  $\rightarrow$  2.8-4.1 MA/cm<sup>2</sup> @ ~ 1.2 µm YBCO
- SP IBAD & buffers/LANL YBCO → 2.3 MA/cm<sup>2</sup> @ 1.5 μm YBCO
- SP continuous process (MOCVD YBCO) → 1.9 meters, 116 A.
- SP IBAD MgO  $\rightarrow$  50 meters, ~ 6° FWHM, 10 meters/hour



#### Scoring criterion – FY2005 plans

Consult with our industrial partners to address strategies of mutual interest for increasing performance and reducing costs.

- ▶ Modify IBAD assist gun to expand deposition zone length to improve process efficiency. *Goal: Double window to 90% of gun length*.
- Improve IBAD MgO texture by reducing divergence of SuperPower's ion-assist gun. *Goal: Routinely obtain*  $\Delta \Phi \leq 5^{\circ}$  *FWHM*.



#### Scoring criterion - FY2005 plans (continued)

- ► Expand upon our data of how YBCO superconducting properties (T<sub>c</sub>, J<sub>c</sub>) are affected by transition metal impurities. *Goal: Determine tolerance limits for substrate elements in YBCO films*.
- ► Continue to refine multilayers to exploit very high J<sub>c</sub>s for thinner YBCO. Goals: Reproducible 1000 A/cm-width in 2.5 μm. Assist industrial partners in implementing multilayer designs appropriate to their deposition technologies.

